FAIRCHILD SEMICONDUCTOR®

March 2006

FDD8780/FDU8780
N-Channel PowerTrench® MOSFET
25V, 35A, 8.5mΩ

General Description

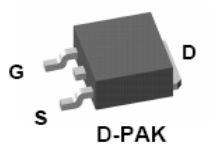
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{DS(on)}$ and fast switching speed.

Application

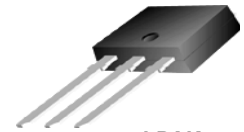
- Vcore DC-DC for Desktop Computers and Servers
- VRM for Intermediate Bus Architecture

Features

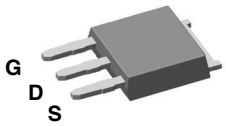
- Max $r_{DS(on)}$ = 8.5mΩ at V_{GS} = 10V, I_D = 35A
- Max $r_{DS(on)}$ = 12.0mΩ at V_{GS} = 4.5V, I_D = 35A
- Low gate charge: $Q_{g(10)}$ = 21nC(Typ), V_{GS} = 10V
- Low gate resistance
- Avalanche rated and 100% tested
- RoHS Compliant



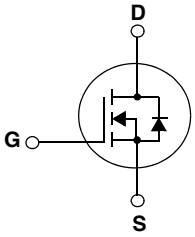
D-PAK
(TO-252)



I-PAK
(TO-251AA)



Short Lead I-PAK



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DS}	Drain to Source Voltage		25	V
V_{GS}	Gate to Source Voltage		±20	V
I_D	Drain Current -Continuous (Package Limited)		35	A
	-Continuous (Die Limited)		60	
	-Pulsed	(Note 1)	224	
E_{AS}	Single Pulse Avalanche Energy	(Note 2)	73	mJ
P_D	Power Dissipation		50	W
T_J, T_{STG}	Operating and Storage Temperature		-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case TO-252,TO-251	3.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,TO-251	100	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,1in^2 copper pad area	52	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8780	FDD8780	TO-252AA	13”	12mm	2500 units
FDU8780	FDU8780	TO-251AA	N/A(Tube)	N/A	75 units
FDU8780	FDU8780_F071	TO-251AA	N/A(Tube)	N/A	75 units

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Electrical Characteristics T_J = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
B_{VDSS}	Drain to Source Breakdown Voltage	I_D = 250μA, V_{GS} = 0V	25			V
$\frac{\Delta B_{VDSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I_D = 250μA, referenced to 25°C		12		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 20V, V_{GS} = 0V			1	μA
		V_{DS} = 20V, V_{GS} = 0V, T_J = 150°C			250	μA
I_{GSS}	Gate to Source Leakage Current	V_{GS} = ±20V			±100	nA
On Characteristics						
$V_{GS(th)}$	Gate to Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 250μA	1.2	1.8	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250μA, referenced to 25°C		-6.3		mV/°C
$r_{DS(on)}$	Drain to Source On Resistance	V_{GS} = 10V, I_D = 35A		6.5	8.5	mΩ
		V_{GS} = 4.5V, I_D = 35A		9.1	12.0	mΩ
		V_{GS} = 10V, I_D = 35A, T_J = 175°C		10.4	15.0	mΩ
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS} = 13V, V_{GS} = 0V, f = 1MHz		1080	1440	pF
C_{oss}	Output Capacitance			265	355	pF
C_{rss}	Reverse Transfer Capacitance			180	270	pF
R_g	Gate Resistance	f = 1MHz		0.9		Ω
Switching Characteristics						
$t_{d(on)}$	Turn-On Delay Time	V_{DD} = 13V, I_D = 35A, V_{GS} = 10V, R_{GS} = 17Ω		7	14	ns
t_r	Rise Time			9	18	ns
$t_{d(off)}$	Turn-Off Delay Time			43	69	ns
t_f	Fall Time			24	38	ns
Q_g	Total Gate Charge	V_{GS} = 0V to 10V, V_{DD} = 13V, I_D = 35A, I_g = 1.0mA		21	29	nC
Q_g	Total Gate Charge	V_{GS} = 0V to 5V, V_{DD} = 13V, I_D = 35A, I_g = 1.0mA		11.2	16	nC
Q_{gs}	Gate to Source Gate Charge	V_{DD} = 13V, I_D = 35A, I_g = 1.0mA		3.5		nC
Q_{gd}	Gate to Drain “Miller”Charge	V_{DD} = 13V, I_D = 35A, I_g = 1.0mA		4.7		nC
Drain-Source Diode Characteristics						
V_{SD}	Source to Drain Diode Forward Voltage	V_{GS} = 0V, I_S = 35A		0.92	1.25	V
		V_{GS} = 0V, I_S = 15A		0.84	1.0	V
t_{rr}	Reverse Recovery Time	I_F = 35A, di/dt = 100A/μs		28	42	ns
Q_{rr}	Reverse Recovery Charge	I_F = 35A, di/dt = 100A/μs		20	30	nC

Notes:
1: Pulse time < 300μs, Duty cycle = 2%.
2: Starting T_J = 25°C, L = 0.3mH, I_{AS} = 22A, V_{DD} = 23V, V_{GS} = 10V.

Typical Characteristics T_J = 25°C unless otherwise noted

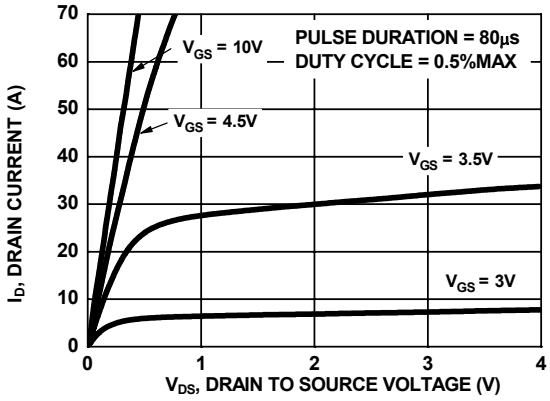

Figure 1. On Region Characteristics

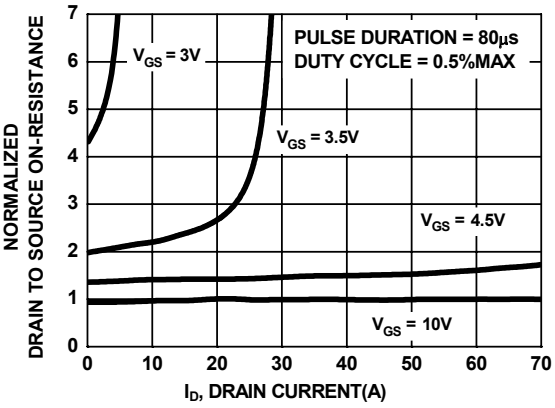

Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

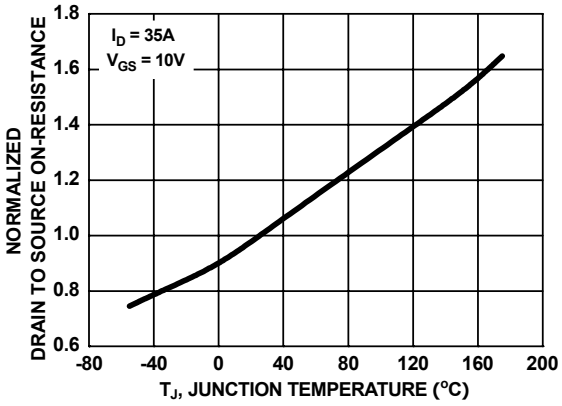

Figure 3. Normalized On Resistance vs Junction Temperature

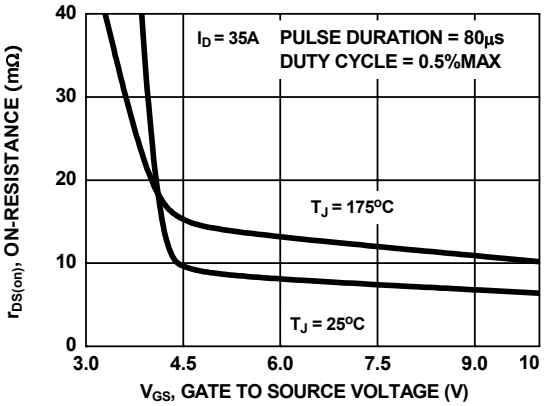

Figure 4. On-Resistance vs Gate to Source Voltage

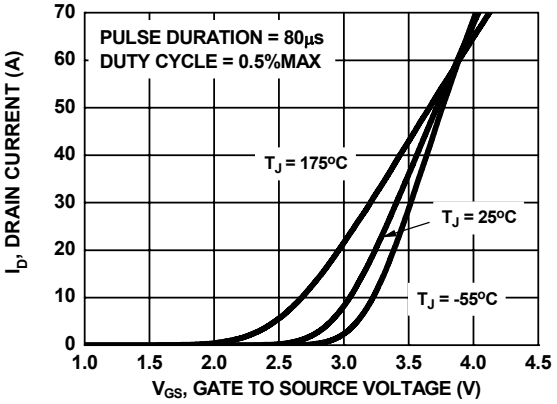

Figure 5. Transfer Characteristics

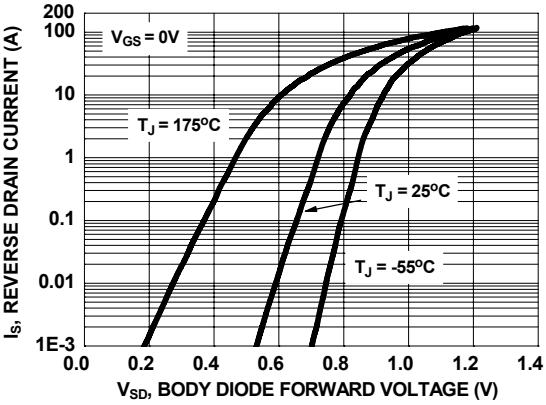

Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

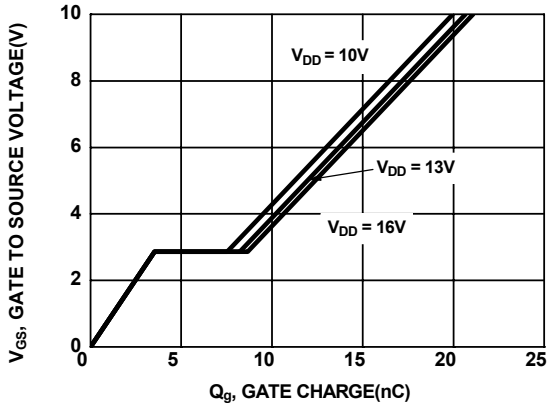

Figure 7. Gate Charge Characteristics

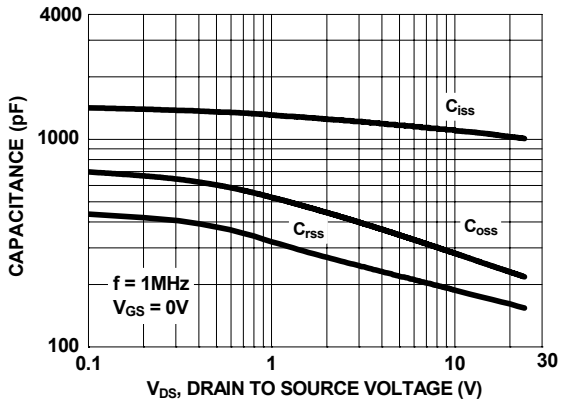

Figure 8. Capacitance vs Drain to Source Voltage

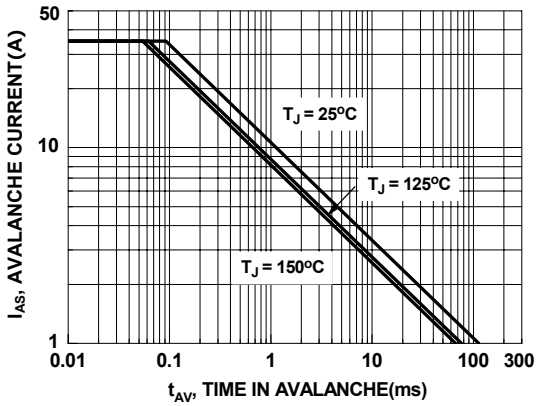

Figure 9. Unclamped Inductive Switching Capability

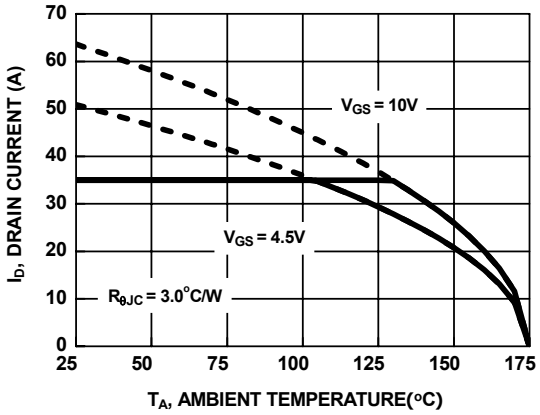

Figure 10. Maximum Continuous Drain Current vs Case Temperature

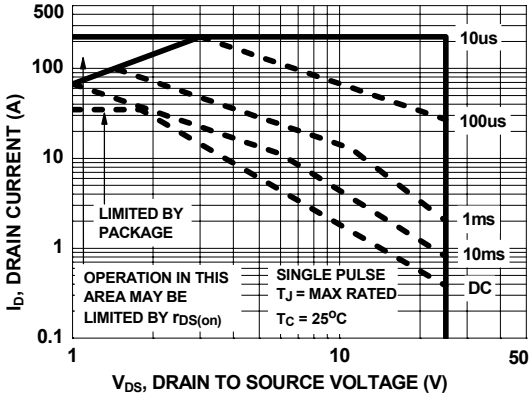

Figure 11. Forward Bias Safe Operating Area

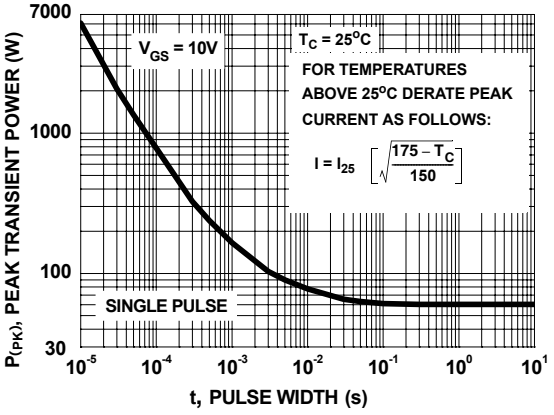

Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25°C unless otherwise noted

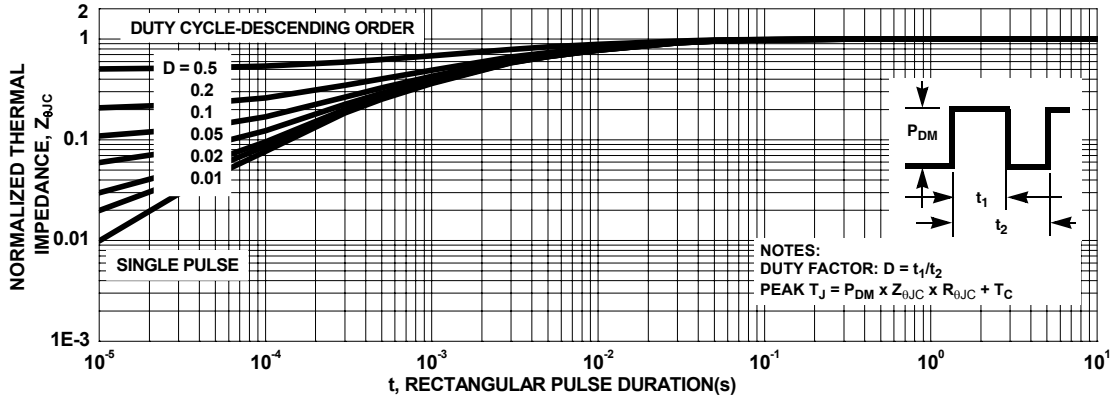

Figure 13. Transient Thermal Response Curve

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Rev. I18